

Abstract Submitted  
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**Ellipsometric study of SrTiO<sub>3</sub> thin film grown Si(100)**

YAO TIAN, University of Toronto, CAROLINA ADAMO, Cornell Center of Materials Research, KENNETH BURCH, University of Toronto — Recently, a new method to grow SrTiO<sub>3</sub> thin ferroelectric film directly on Si(100) has been demonstrated by *M. P. Warusawithana, et al.* We use ellipsometry to study the film and a model based on inhomogenous gap to oxide deficiency was made to interpret the data.

Yao Tian  
University of Toronto

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